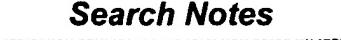


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/789,103	WU ET AL.	
	Examiner	Art Unit	
	B. Chen	1762	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner